



H1M120Q060

Silicon Carbide MOSFET
N-CHANNEL ENHANCEMENT MODE

Features

- Low On-Resistance and High Current Density
- Low Capacitance for High Frequency Operation
- Positive Temperature Coefficient Device
- Low impedance Kelvin source pin-out
- AEC-Q101 Qualified
- RoHS Compliant and Halogen Free

Benefits

- Higher System Efficiency
- Increase Parallel Device Convenience
- Capable of 175°C High T_j Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems

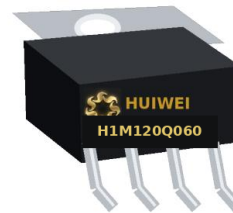
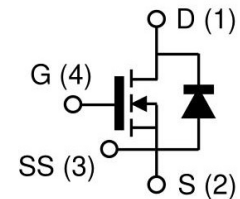
Applications

- Switching Mode Power Supply
- DC/DC Converters, UPS, and PFC
- EV Charging Station
- Motor Drives
- Power Inverters
- Solar/Wind Renewable Energy

V_{DS} 1200V
 $I_D(@25^{\circ}C)$ 45A
 $R_{DS(on)}$ 60mΩ



Circuit Diagram



Part Number	Package	Marking
H1M120Q060	TO-247-4L	H1M120Q060

Description

The H1M120Q060 1200V, 60mΩ silicon carbide power MOSFET is an N-channel enhancement mode device. Exploiting the outstanding wide bandgap material properties, this device shows high current density and great switching behavior. Thanks for the excellent thermal conductivity and many advantages of SiC, this device significantly improved in thermal capability and temperature independent switching behavior. With the high stability and reliability, this device also passes the qualification criteria based on AEC-Q101.

Absolute Maximum Ratings ($T_c = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Drain – Source Voltage	$V_{DS, max}$	$V_{GS}=0V, I_{DS}=100\mu A$	1200	V
Continuous Drain Current	I_D	$V_{GS}=20V, T_c=25^{\circ}C$	45	A
		$V_{GS}=20V, T_c=110^{\circ}C$	31	
Pulse Drain Current	$I_{D, pulse}$	t_{PW} limitation per Fig.15	91	
Avalanche energy, Single Pulse	E_{AS}	$V_{DD}=100V, I_D=10A$	1250	mJ
Power Dissipation	P_D	$T_c=25^{\circ}C$	258	W
Recommend Gate Source Voltage	$V_{GS, op}$	Static, recommended DC operating values	-5 to 20	V
Maximum Gate Source Voltage	$V_{GS, max}$	Transient operating limit (AC f > 1Hz, duty cycle < 1%)	-10 to 25	
Junction & Storage Temperature	T_j, T_{stg}		-55 to 175	$^{\circ}C$
Soldering Temperature	T_L		260	
Mounting Torque	M_D	M3 or 6-32 screw	1.0	Nm

Thermal Resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$		0.58		$^{\circ}C/W$

**Electrical Characteristics** ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_{DS}=100\mu A$	1200			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=10V, I_{DS}=20mA$		2.85		V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=1200V, V_{GS}=0V$		<1	50	μA
		$V_{DS}=1200V, V_{GS}=0V$ $T_j=175^\circ\text{C}$		10	500	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=20V, V_{DS}=0V$			250	nA
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS}=20V, I_{DS}=20A$		60	80	mΩ
		$V_{GS}=20V, I_{DS}=20A$, $T_j=175^\circ\text{C}$		100		
Transconductance	g_{fs}	$V_{DS}=12.5V, I_{DS}=40A$		10.5		S
Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=800V$ $f=1MHz, V_{AC}=25mV$		2200		pF
Output Capacitance	C_{oss}			115		
Reverse Transfer Capacitance	C_{rss}			18.5		
Effective Output Capacitance, Energy Related	$C_{o(er)}$	$V_{GS}=0V$, $V_{DS}=0$ to 800V		150		
Effective Output Capacitance, Time Related	$C_{o(tr)}$	$I_D=const.$, $V_{GS}=0V$, $V_{DS}=0$ to 800V		211		
Turn On Delay Time	$t_{d(on)}$	$V_{DS}=800V, V_{GS}=-4/20V$, $I_D=20A, R_L=40\Omega$, $R_{G(ext)}=2.7\Omega$		25		ns
Rise Time	t_r			24		
Turn Off Delay Time	$t_{d(off)}$			20		
Fall Time	t_f			9		
C_{oss} Stored Energy	E_{oss}	$V_{GS}=0V, V_{DS}=800V$ $f=1MHz, V_{AC}=25mV$		47		μJ
Turn-on Switching Energy	E_{on}	$V_{DS}=800V, V_{GS}=0/20V$, $I_D=20A$,		240		
Turn-off Switching Energy	E_{off}	$R_{G(ext)}=2.7\Omega$		51.2		
Internal Gate Resistance	$R_{G(int.)}$	$f=1MHz, V_{AC}=25mV$		1.2		Ω

Built-in SiC Diode Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Typ.	Unit
Inverse Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_{SD}=5A$	3.5	V
Continuous Diode Forward Current	I_S	$V_{GS}=0V, T_c=25^\circ\text{C}$	44	A
Reverse Recovery Time	t_{rr}	$V_{GS}=0V$,	57	ns
Reverse Recovery Charge	Q_{rr}	$I_{SD}=20A, V_{DS}=400V$,	109	nC
Peak Reverse Recovery Current	I_{rrm}	$di/dt=300A/\mu s$	3.5	A

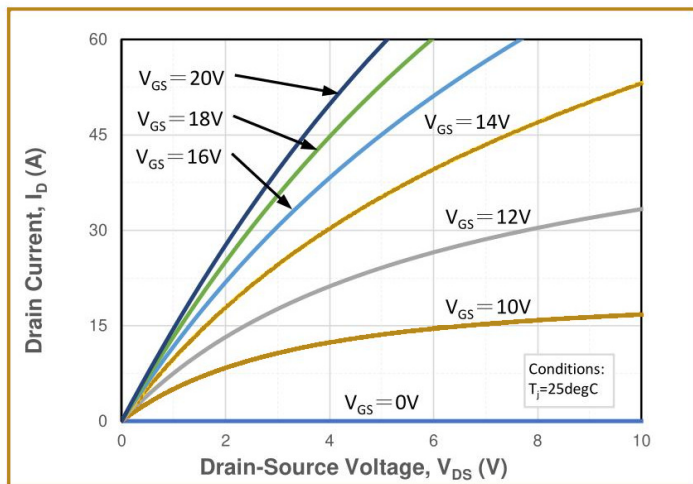
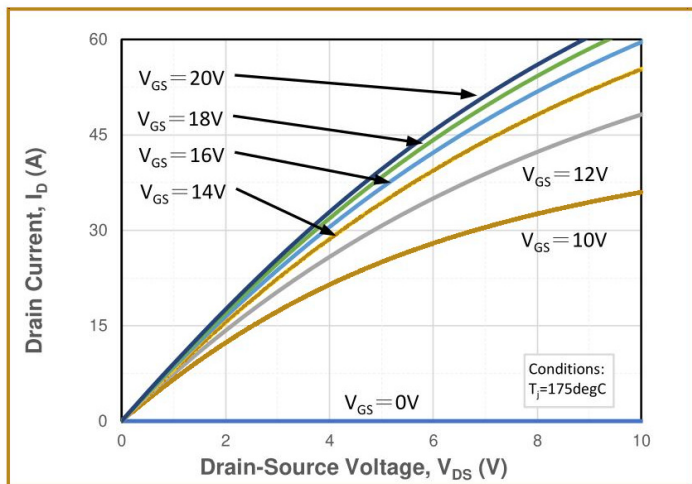
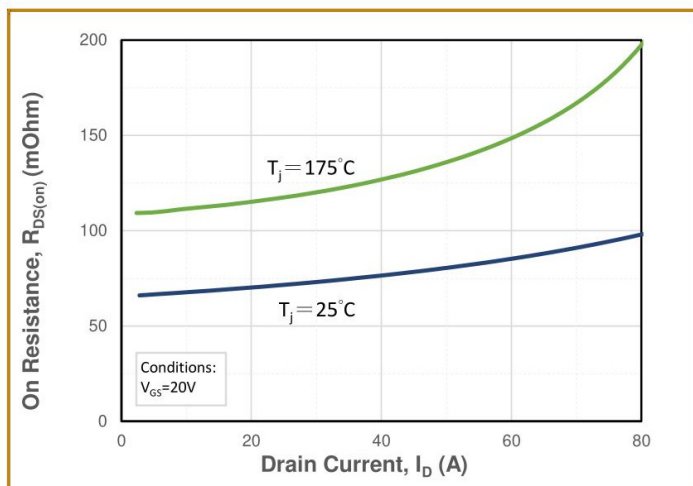
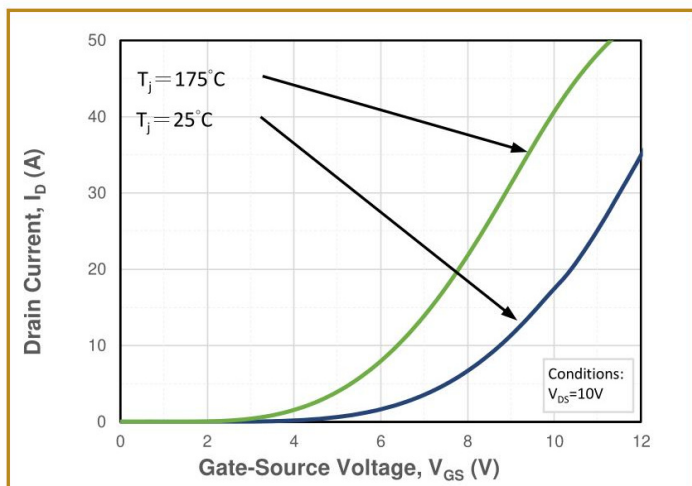
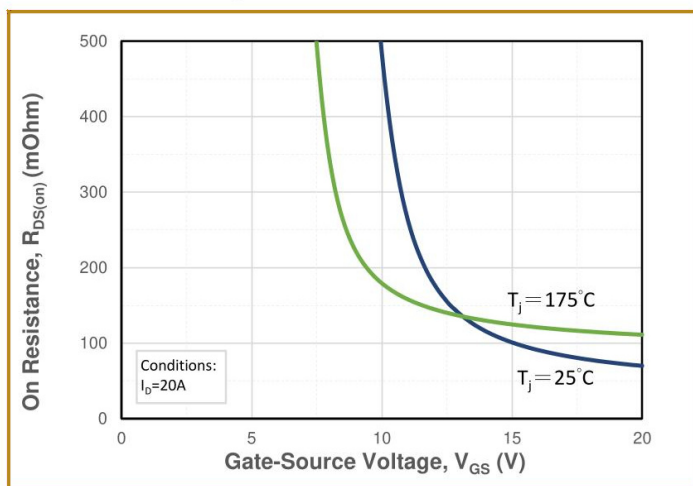
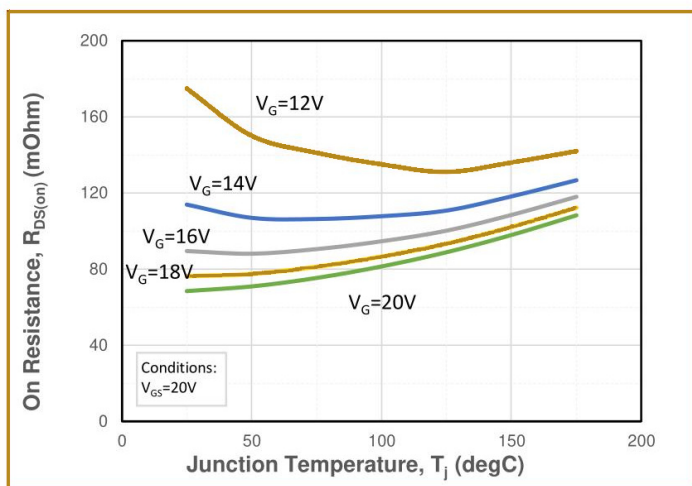
*Based on the results of calculation, note that the energy loss caused by the reverse recovery of free-wheeling diode is not included in E_{on} .

Gate Charge Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Gate to Source Charge	Q_{GS}	$V_{DS}=800V$, $V_{GS}=-5/+20V$, $I_D=20A$	29	nC
Gate to Drain Charge	Q_{GD}		64	
Total Gate Charge	Q_G		129	
Gate plateau voltage	V_{pl}		6.95	V



Typical Device Performance

**Fig.1 Forward Output Characteristics at $T_j=25^\circ\text{C}$** **Fig.2 Forward Output Characteristics at $T_j=175^\circ\text{C}$** **Fig.3 On-Resistance vs. Drain Current for Various T_j** **Fig.4 Transfer Characteristics for Various T_j** **Fig.5 On-Resistance vs. Gate Voltage for Various T_j** **Fig.6 On-Resistance vs. Temperature for Various Gate Voltage**



Typical Device Performance

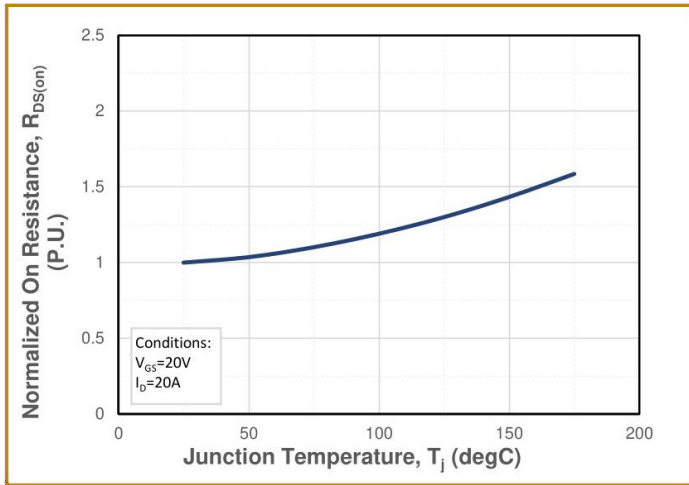


Fig.7 Normalized On-Resistance vs. Temperature

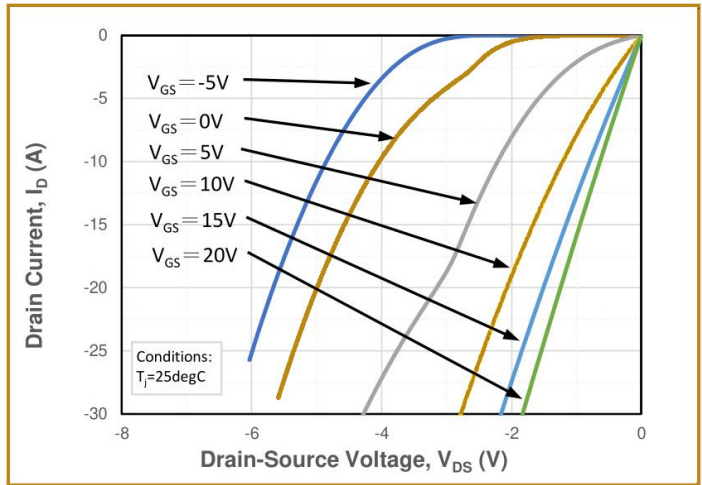


Fig.8 Reverse Output Characteristics at $T_J = 25^\circ C$

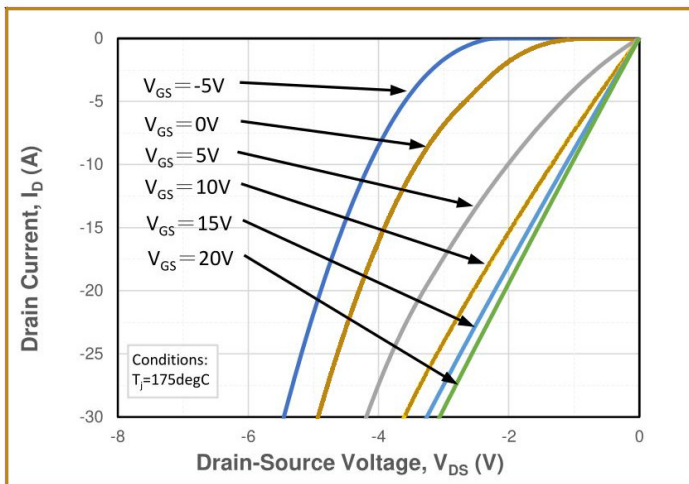


Fig.9 Reverse Output Characteristics at $T_J = 175^\circ C$

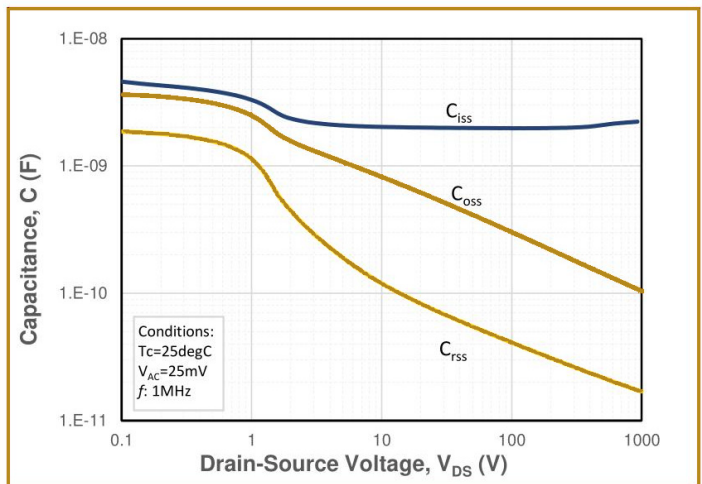


Fig.10 Capacitances vs. Drain to Source Voltage

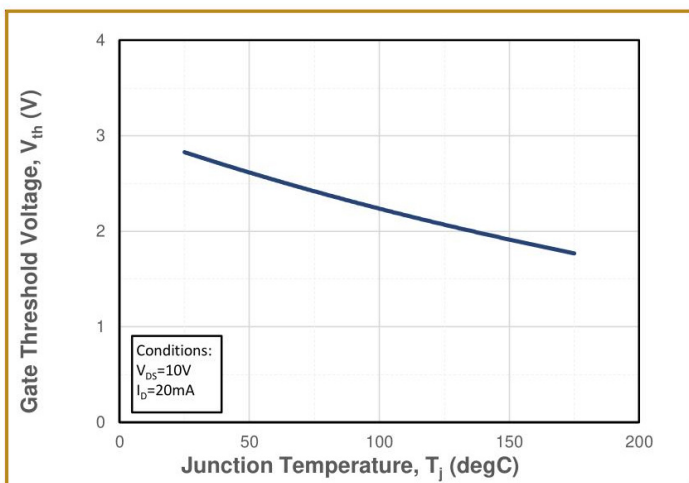


Fig.11 Threshold Voltage vs. Temperature

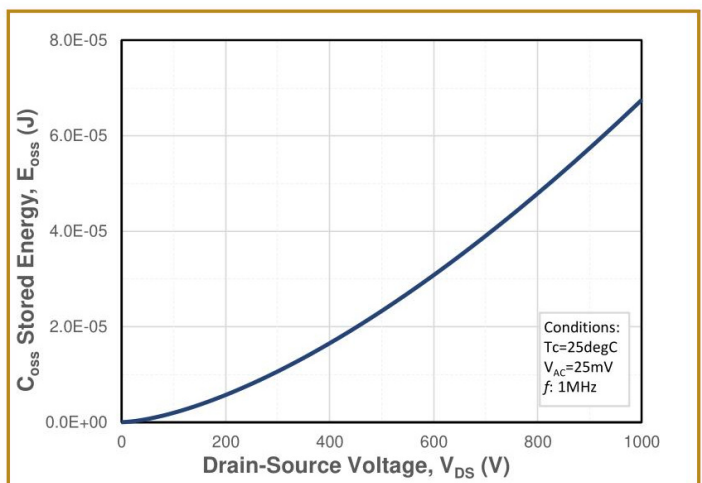


Fig.12 Output Capacitor Stored Energy



Typical Device Performance

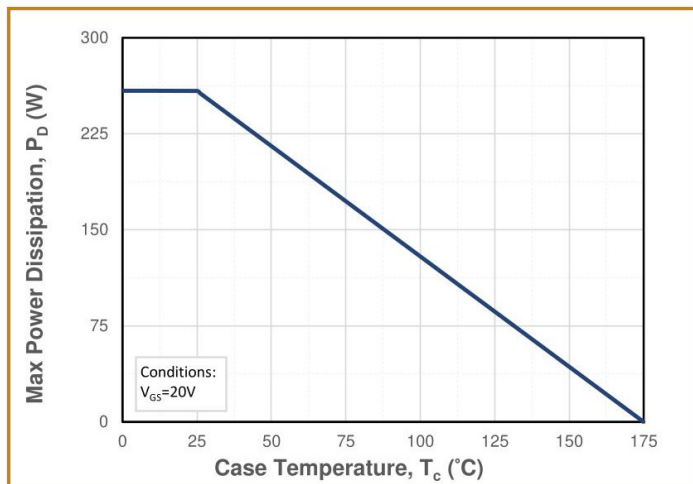


Fig.13 Maximum Power Dissipation Derating vs. Case Temperature

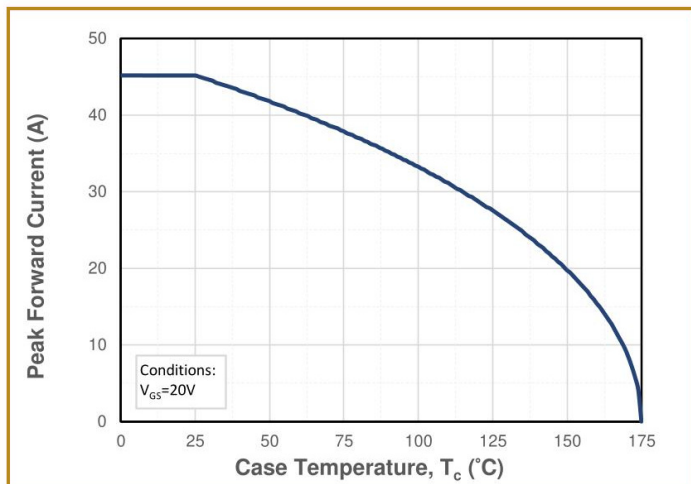


Fig.14 Drain Current Derating vs. Case Temperature

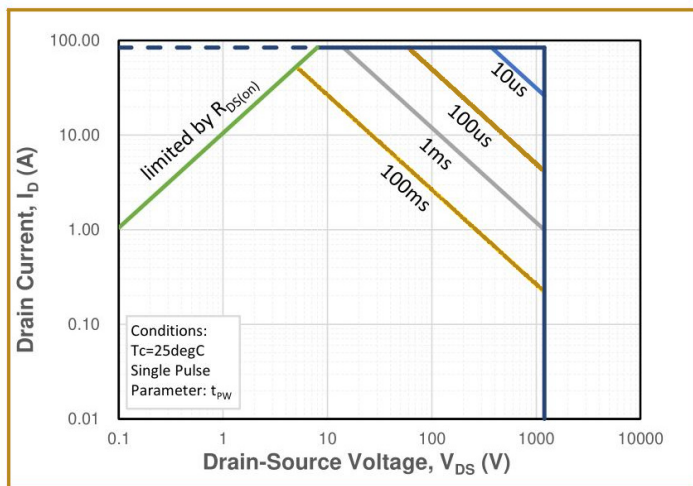


Fig.15 Safe Operating Area

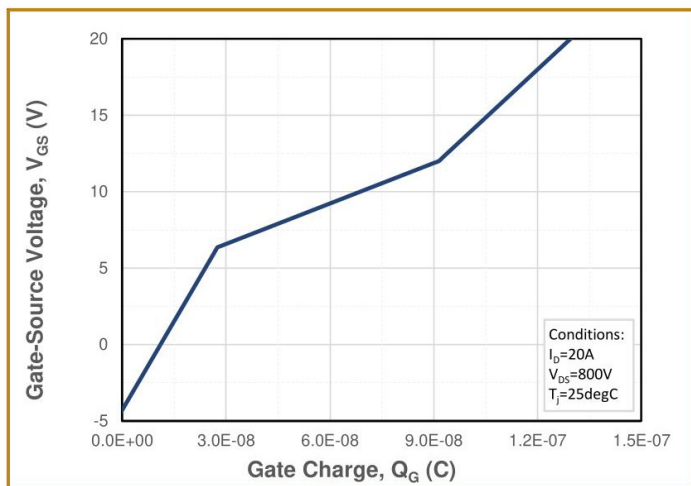


Fig.16 Gate Charge Characteristics

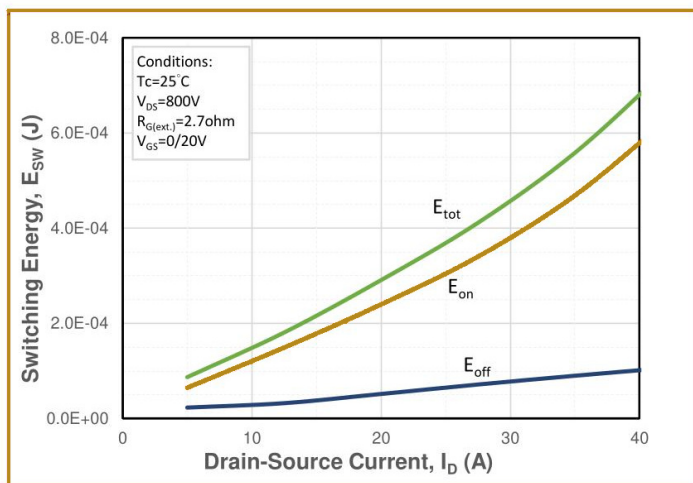


Fig.17 Clamped Inductive Switching Energy vs. Drain Current

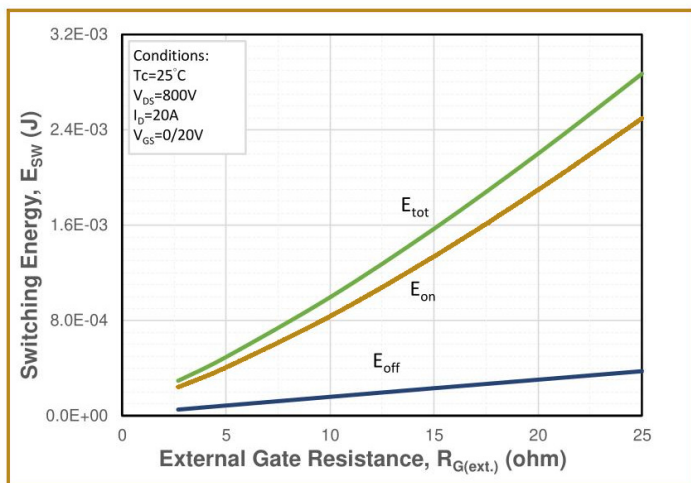


Fig.18 Clamped Inductive Switching Energy vs. External Gate Resistor ($R_{G(ext.)}$)



Typical Device Performance

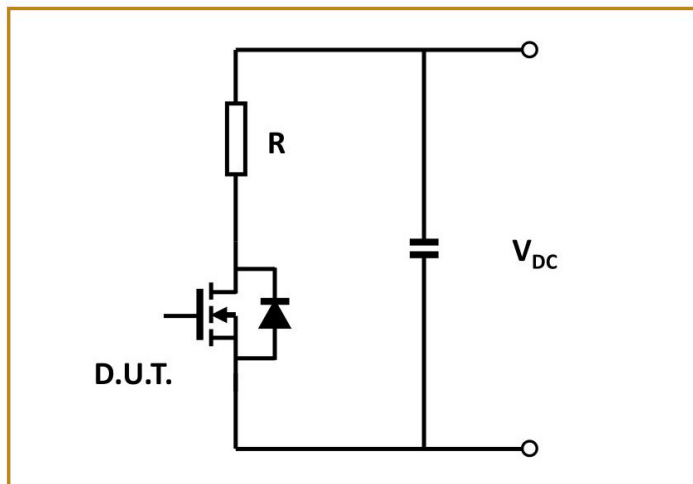


Fig.19 Schematic of Resistive Switching

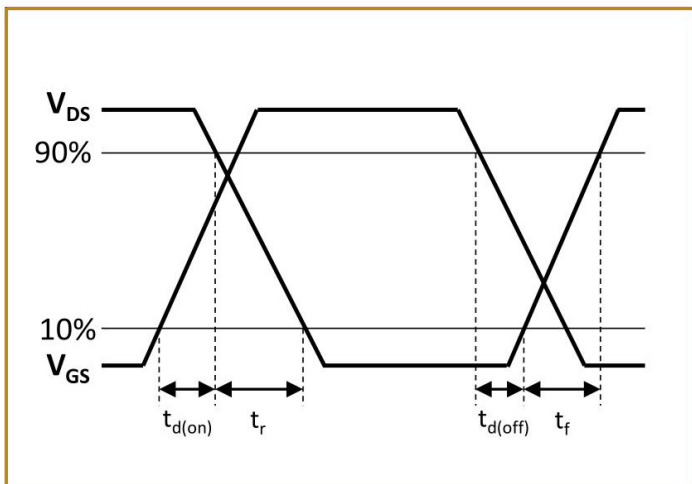


Fig.20 Switching Times Definition

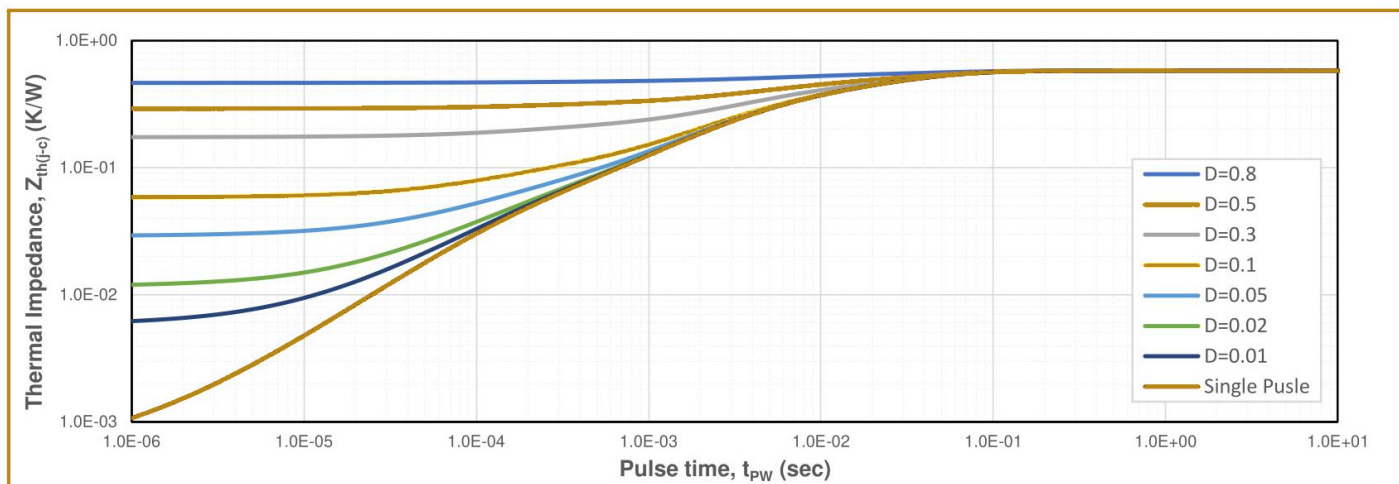


Fig.21 Transient Junction to Case Thermal Impedance

Naming Rule

H1 M 120 Q 060

Generation

H1 = 1st Gen Discrete

Device Type

M = MOSFET J = J MOS

S = JBS diode

Breakdown Voltage

065 = 650V 170 = 1700V

120 = 1200V 330 = 3300V

Package

Q = TO-247-4L B = TO-220-3L

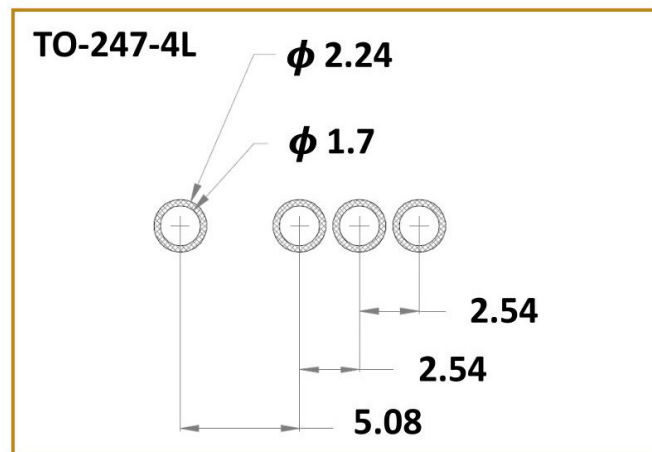
T = TO-263-2L N = Bare Die

Typical On-Resistance

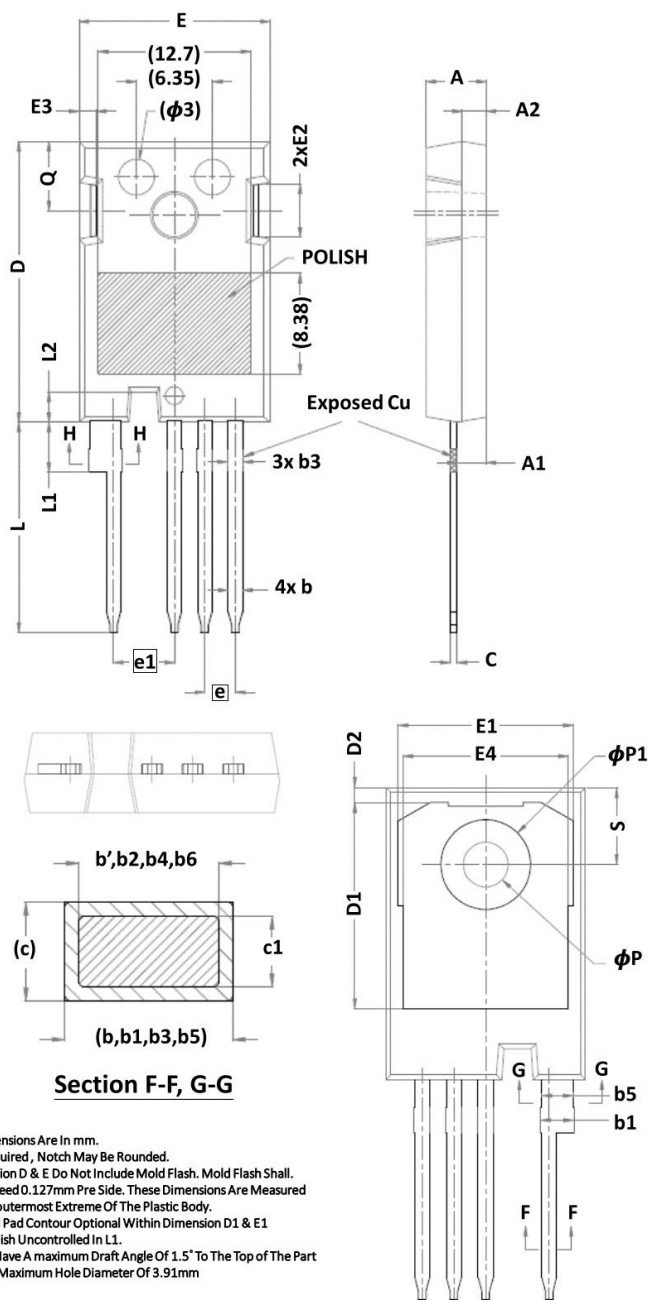
030 = 30mΩ 060 = 60mΩ 120 = 120mΩ

240 = 240mΩ

Recommended Solder Pad Layout



Package Dimensions



Symbol	mm		
	Min.	Typ.	Max.
A	4.83	5.02	5.21
A1	2.29	2.41	2.54
A2	1.91	2.00	2.16
b'	1.07	1.20	1.28
b	1.07	1.20	1.33
b1	2.39	2.67	2.94
b2	2.39	2.67	2.84
b3	1.07	1.30	1.60
b4	1.07	1.30	1.50
b5	2.39	2.53	2.69
b6	2.39	2.53	2.64
c	0.55	0.60	0.68
c1	0.55	0.60	0.65
D	23.30	23.45	23.60
D1	16.25	16.55	17.65
D2	0.95	1.19	1.25
E	15.75	15.94	16.13
E1	13.10	14.02	14.15
E2	3.68	4.40	5.10
E3	1.00	1.45	1.90
E4	12.38	13.26	13.43
e	2.54 BSC		
e1	5.08 BSC		
L	17.31	17.57	17.82
L1	3.97	4.19	4.37
L2	2.35	2.50	2.65
ϕ P	3.51	3.61	3.65
ϕ P1	7.19 REF.		
Q	5.49	5.79	6.00
S	6.04	6.17	6.30

Notes

- The information provided herein is subject to change without notice.
- For other information that does not show on this datasheet, please contact us for inquiry.